	Hit		
	g	Search Text	DBs
1	8	(("6191397") or ("6603101") or ("6550990") or ("6483083") or ("6495807") or ("6441351") or ("6376139") or ("6333493")).PN.	USPAT; US-PGPUB
2		(heat\$4 with (apparatus or system)) and ((plate or surface or holder) same (heat\$4 or bak\$4) same support same (wafer or substrate)) and (((partition with member) or electrode or ((charg\$3 or ceramic) near2 plate)) same (permeable or permeat\$3 or porous)) and ((air or gas or nitrogen) with (purge or stream or port))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
3		(heat\$4 with (apparatus or system)) and ((plate or surface or holder) same (heat\$4 or bak\$4) same support same (wafer or substrate) same ((partition with member) or electrode or ((charg\$3 or ceramic or absorption) near2 plate)) same (permeable or permeat\$3 or porous)) and ((air or gas or nitrogen) with (purge or stream or port))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
4	2	amplifed poor? regist)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Hit	Search Text	
-	s		DBs
5	21	(heat\$4 with (apparatus or system)) and ((plate or surface or holder) same (heat\$4 or bak\$4) same support same (wafer or substrate)) and ((wafer or substrate or workpiece) same (resist or photoresist or (acid with generat\$4) or (acid with liberat\$4) or (chemical\$2 near2 amplif\$4 near3 resist))) and (((partition with member) or electrode or ((charg\$3 or ceramic or absorption) near2 plate)) same (permeable or permeat\$3 or porous)) and ((air or gas or nitrogen) with (purge or stream or port))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
6	68	(heat\$4 with (apparatus or system)) and ((plate or surface or holder) same (heat\$4 or bak\$4) same support same (wafer or substrate)) and ((wafer or substrate or workpiece) same (resist or photoresist or (acid with generat\$4) or (acid with liberat\$4) or (chemical\$2 near2 amplif\$4 near3 resist)) same ((partition with member) or electrode or ((charg\$3 or ceramic or absorption) near2 plate))) and ((air or gas or nitrogen) with (purge or stream or port or inlet))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	2	or absorption) many all h	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
3	8	("6376139") or ("6333493")).PN.	USPAT; US-PGPUB
9	0]	("L22and(resistorphotoresist)").P N.	USPAT; US-PGPUB

	Hit s	Search Text	DBs
10	2	((plate or holder or (support near3 surface)) same (heat\$4 or bak\$4 or post\$2bak\$3 or post\$2expos\$4bak\$3 or PEB) same support same (wafer or substrate) same (resist or photoresist)) and (((partition with member) or electrode or ((charg\$3 or ceramic or absorption) near2 plate) or (electric with field) or (temperature with control\$5)) same (permeable or permeat\$3 or porous) same ((air or gas or nitrogen) with (purge or stream or port))) and (system or apparatus or chamber)	
11	1	("20020123011").PN.	USPAT; US-PGPUB
12	1		USPAT; US-PGPUB
13	8	electrode or member or plate))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB